

Notice of References Cited

Application/Control No.

10/598,218

Applicant(s)/Patent Under

Reexamination

BAE ET AL.

Examiner

MICHAEL R. VAUGHAN

Art Unit

2431

Page 1 of 1

U.S. PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|--|-----------------|-------------------|----------------|
| * | A US-6,108,719 A | 08-2000 | Klein, Dean A. | 710/10 |
| * | B US-6,272,611 B1 | 08-2001 | Wu, Yu-Te | 711/173 |
| * | C US-2004/0010701 A1 | 01-2004 | Umebayashi et al. | 713/193 |
| * | D US-2004/0186971 A1 | 09-2004 | Meharchand et al. | 711/163 |
| * | E US-7,000,250 B1 | 02-2006 | Kuo et al. | 726/22 |
| * | F US-2007/0050620 A1 | 03-2007 | Pham et al. | 713/165 |
| * | G US-7,603,533 B1 | 10-2009 | Tsypliaev et al. | 711/167 |
| H | US- | | | |
| I | US- | | | |
| J | US- | | | |
| K | US- | | | |
| L | US- | | | |
| M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|--|-----------------|---------|------|----------------|
| N | | | | | |
| O | | | | | |
| P | | | | | |
| Q | | | | | |
| R | | | | | |
| S | | | | | |
| T | | | | | |

NON-PATENT DOCUMENTS

| * | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|
| U | |
| V | |
| W | |
| X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.